

- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

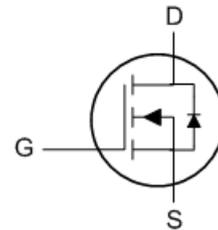
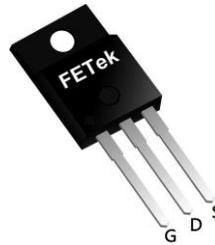
**Product Summary**

| BVDSS | RDSON | ID  |
|-------|-------|-----|
| 100V  | 22mΩ  | 27A |

**Description**

The FKF0018A is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The FKF0018A meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

**TO220F Pin Configuration**

**Absolute Maximum Ratings**

| Symbol                                | Parameter                                  | Rating     | Units |
|---------------------------------------|--|------------|-------|
| V <sub>DS</sub>                       | Drain-Source Voltage                       | 100        | V     |
| V <sub>GS</sub>                       | Gate-Source Voltage                        | ±20        | V     |
| I <sub>D</sub> @T <sub>C</sub> =25°C  | Continuous Drain Current                   | 27         | A     |
| I <sub>D</sub> @T <sub>C</sub> =100°C | Continuous Drain Current                   | 19         | A     |
| I <sub>D</sub> @T <sub>A</sub> =25°C  | Continuous Drain Current                   | 6          | A     |
| I <sub>D</sub> @T <sub>A</sub> =70°C  | Continuous Drain Current                   | 5          | A     |
| I <sub>DM</sub>                       | Pulsed Drain Current <sup>2</sup>          | 120        | A     |
| EAS                                   | Single Pulse Avalanche Energy <sup>3</sup> | 48         | mJ    |
| I <sub>AS</sub>                       | Avalanche Current                          | 31         | A     |
| P <sub>D</sub> @T <sub>C</sub> =25°C  | Total Power Dissipation <sup>4</sup>       | 38.5       | W     |
| P <sub>D</sub> @T <sub>A</sub> =70°C  | Total Power Dissipation <sup>4</sup>       | 1.5        | W     |
| T <sub>STG</sub>                      | Storage Temperature Range                  | -55 to 175 | °C    |
| T <sub>J</sub>                        | Operating Junction Temperature Range       | -55 to 175 | °C    |

**Thermal Data**

| Symbol           | Parameter  | Typ. | Max. | Unit |
|------------------|--|------|------|------|
| R <sub>θJA</sub> | Thermal Resistance Junction-Ambient <sup>1</sup> | ---  | 58   | °C/W |
| R <sub>θJC</sub> | Thermal Resistance Junction-Case <sup>1</sup>    | ---  | 3.9  | °C/W |

**Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)**

| Symbol       | Parameter                                      | Conditions                                       | Min. | Typ. | Max.      | Unit       |
|--------------|--|--|------|------|-----------|------------|
| $BV_{DSS}$   | Drain-Source Breakdown Voltage                 | $V_{GS}=0V, I_D=250\mu A$                        | 100  | ---  | ---       | V          |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance <sup>2</sup> | $V_{GS}=10V, I_D=20A$                            | ---  | 18   | 22        | m $\Omega$ |
| $V_{GS(th)}$ | Gate Threshold Voltage                         | $V_{GS}=V_{DS}, I_D=250\mu A$                    | 2.5  | ---  | 4.5       | V          |
| $I_{DSS}$    | Drain-Source Leakage Current                   | $V_{DS}=100V, V_{GS}=0V, T_J=25^\circ\text{C}$   | ---  | ---  | 10        | uA         |
|              |  | $V_{DS}=100V, V_{GS}=0V, T_J=55^\circ\text{C}$   | ---  | ---  | 50        |            |
| $I_{GSS}$    | Gate-Source Leakage Current                    | $V_{GS}=\pm 20V, V_{DS}=0V$                      | ---  | ---  | $\pm 100$ | nA         |
| $g_{fs}$     | Forward Transconductance                       | $V_{DS}=5V, I_D=20A$                             | ---  | 33   | ---       | S          |
| $Q_g$        | Total Gate Charge (10V)                        | $V_{DS}=80V, V_{GS}=10V, I_D=20A$                | ---  | 27.6 | ---       | nC         |
| $Q_{gs}$     | Gate-Source Charge                             |  | ---  | 11.4 | ---       |            |
| $Q_{gd}$     | Gate-Drain Charge                              |  | ---  | 7.9  | ---       |            |
| $T_{d(on)}$  | Turn-On Delay Time                             | $V_{DD}=50V, V_{GS}=10V, R_G=3.3\Omega, I_D=20A$ | ---  | 16.5 | ---       | ns         |
| $T_r$        | Rise Time                                      |  | ---  | 35   | ---       |            |
| $T_{d(off)}$ | Turn-Off Delay Time                            |  | ---  | 17.5 | ---       |            |
| $T_f$        | Fall Time                                      |  | ---  | 12   | ---       |            |
| $C_{iss}$    | Input Capacitance                              | $V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$           | ---  | 1890 | ---       | pF         |
| $C_{oss}$    | Output Capacitance                             |  | ---  | 268  | ---       |            |
| $C_{rss}$    | Reverse Transfer Capacitance                   |  | ---  | 67   | ---       |            |

**Diode Characteristics**

| Symbol   | Parameter                                | Conditions                                | Min. | Typ. | Max. | Unit |
|----------|--|---|------|------|------|------|
| $I_S$    | Continuous Source Current <sup>1,5</sup> | $V_G=V_D=0V$ , Force Current              | ---  | ---  | 40   | A    |
| $V_{SD}$ | Diode Forward Voltage <sup>2</sup>       | $V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$ | ---  | ---  | 1.2  | V    |
| $t_{rr}$ | Reverse Recovery Time                    | $I_F=20A, di/dt=100A/\mu s$ ,             | ---  | 22   | ---  | nS   |
| $Q_{rr}$ | Reverse Recovery Charge                  | $T_J=25^\circ\text{C}$                    | ---  | 20   | ---  |      |

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $V_{DS}=25V, V_{GS}=10V, L=0.1\text{mH}, I_{AS}=31A$
- 4.The power dissipation is limited by  $175^\circ\text{C}$  junction temperature
- 5.The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

Typical Characteristics

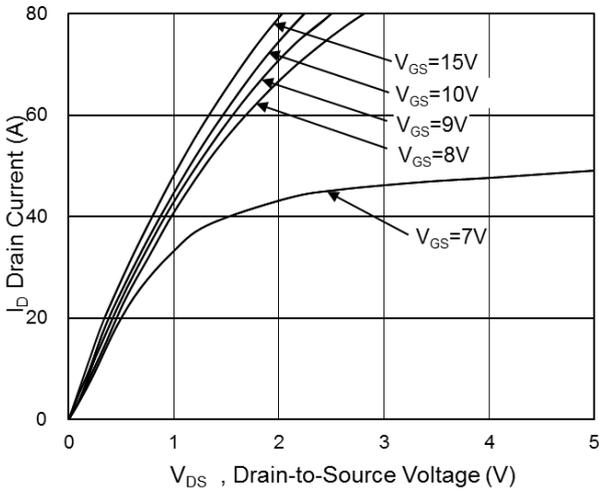


Fig.1 Typical Output Characteristics

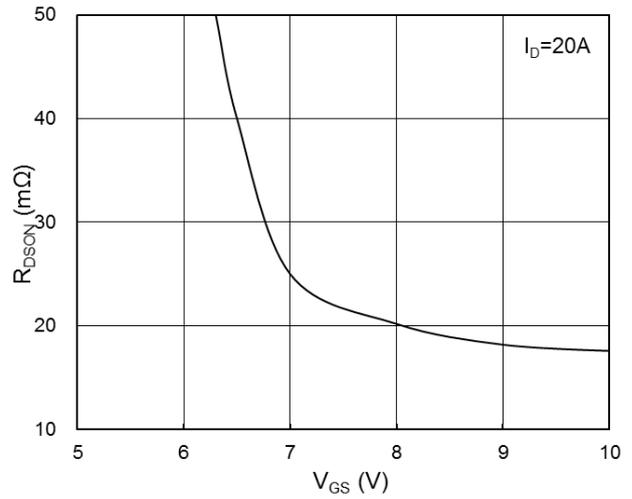


Fig.2 On-Resistance vs. G-S Voltage

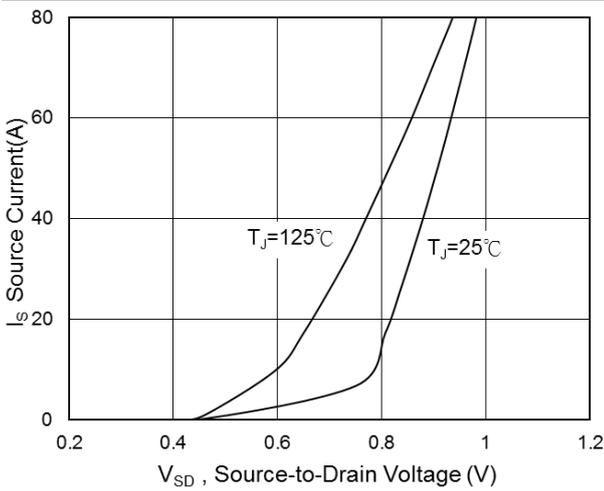


Fig.3 Source Drain Forward Characteristics

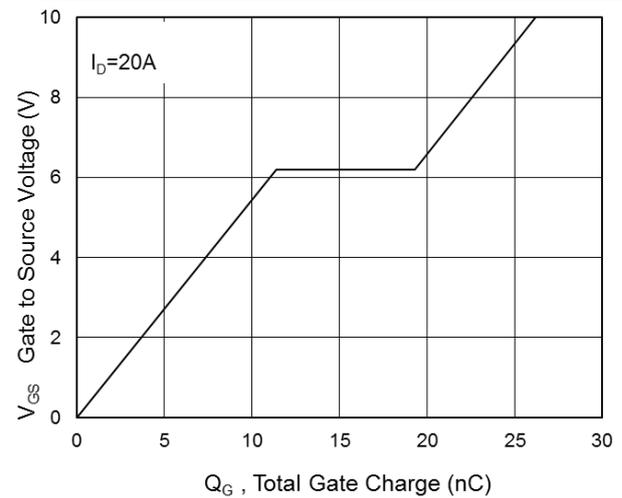


Fig.4 Gate-Charge Characteristics

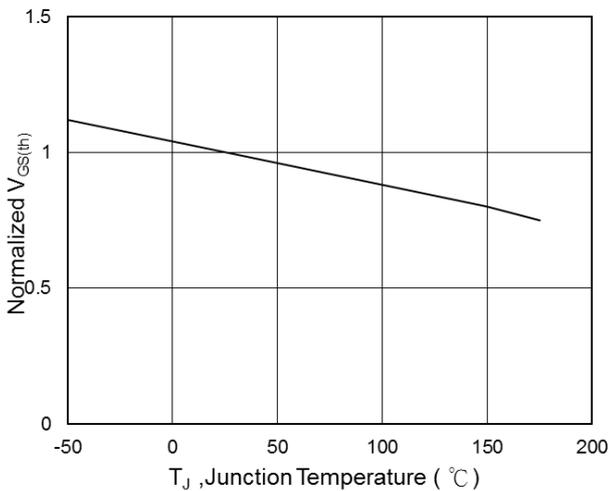


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$

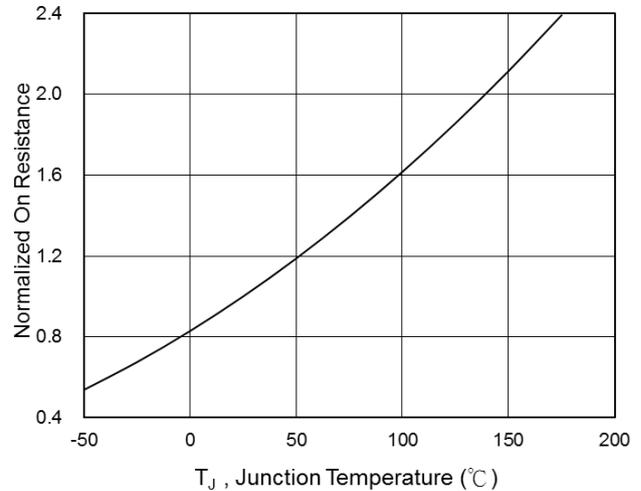


Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$

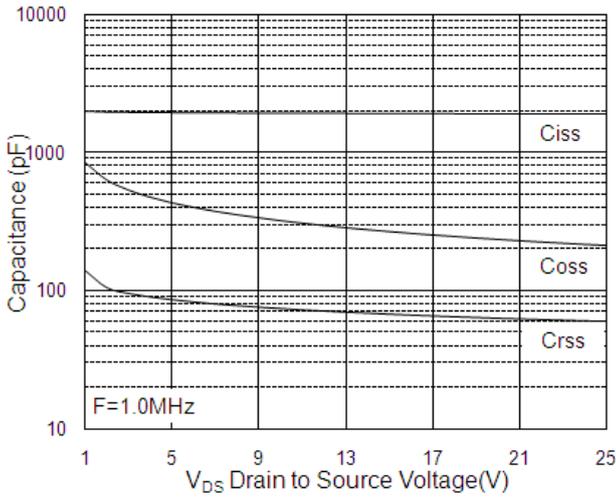


Fig.7 Capacitance

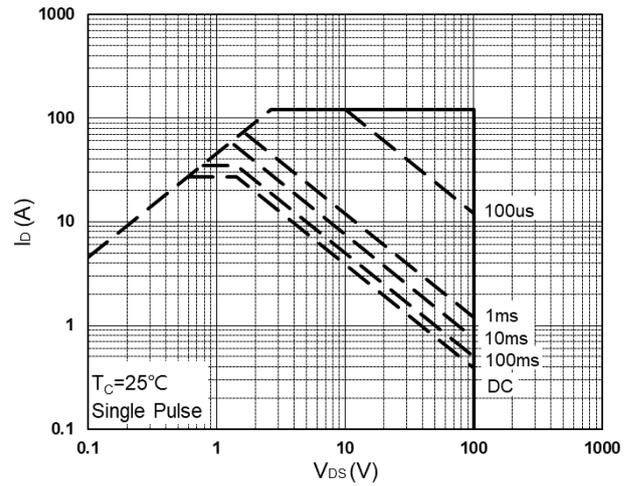


Fig.8 Safe Operating Area

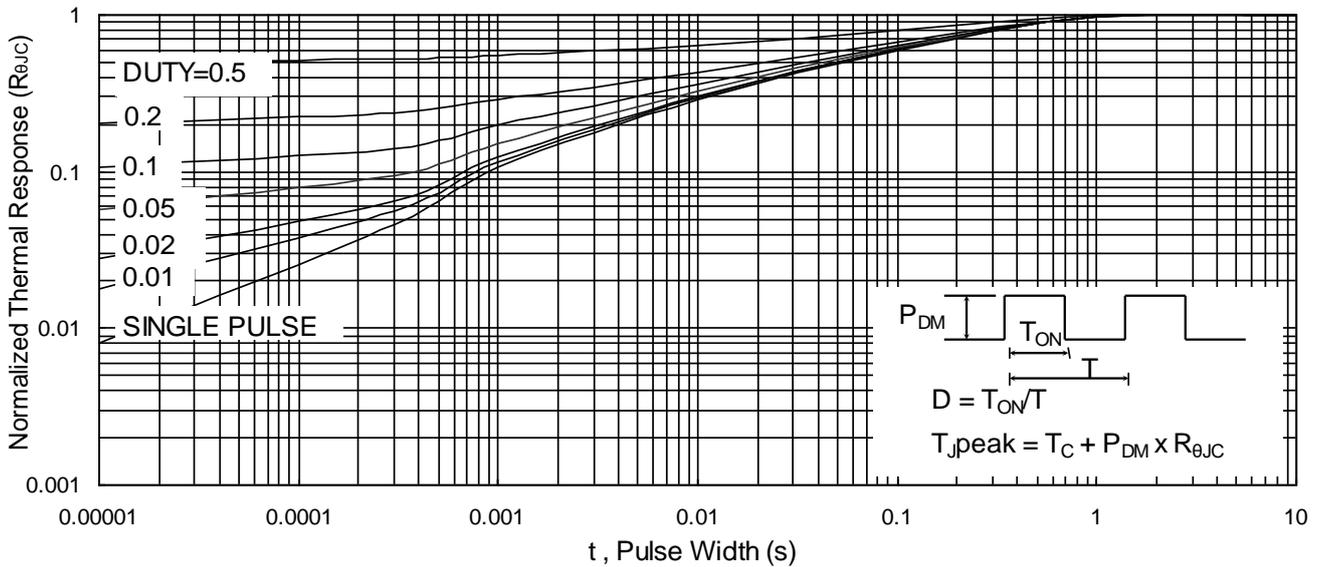


Fig.9 Normalized Maximum Transient Thermal Impedance

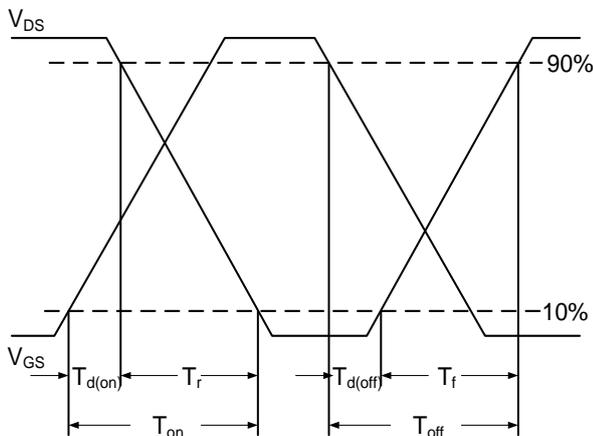


Fig.10 Switching Time Waveform

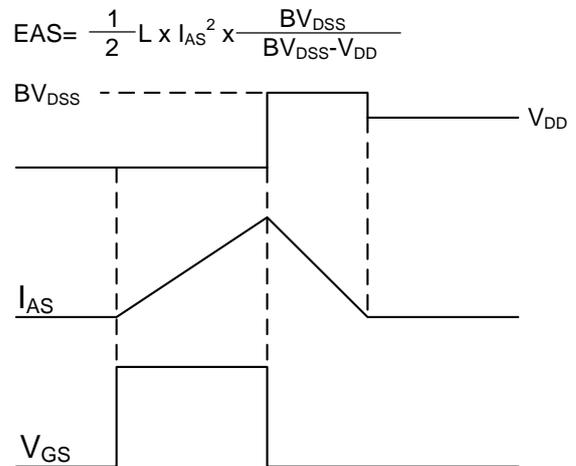


Fig.11 Unclamped Inductive Waveform